

Notice of References Cited	Application/Control No. 10/690,196	Applicant(s)/Patent Under Reexamination GARDELLA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	U	Saito et al. "TOF-SIMS analysis of chemical state changes in cresol-novolac photoresist surface caused by O2 plasma downstream", Applied Surface Science (1999), 142(1-4), 460-464
	V	Davies et al. "Probing the surface chemical structure of some novel poly(ortho esters) prepared with N-methyl and N-phenyl ethanolamine by ... (ToF-SIMS)", Polymers for Advanced Technologies, September 1999, v. 3, pp. 293-301
	W	Chen et al. "Time-of-Flight Secondary Ion Mass Spectrometry studies of in vitro hydrolytic degradation of biodegradable polymers", Macromolecules, 1999, v. 32, pp. 7380-7388
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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